

信頼性試験結果
Reliability Test

XD6138 シリーズ

XD6138 Series

パッケージ

:

SOT-25

AEC-Q100 Grade 1

RoHS対応品 / RoHS Compliance

ハロゲン&アンチモンフリー / Halogen & Antimony-Free

No.	Test Item	Test Conditions		Hours	Sample Size/Lot	Number of Lots	Result r/n
1	PC Preconditioning	TC(-40°C to 60°C 5cyc)→85°C/85%RH168h→260°CReflow Moisture Sensitivity Level 1 Moisture Preconditioning for HAST, UHAST & TC		3 times	77	3	0/231
2	HAST Highly Accelerated Stress Test	130°C85%RH, VIN=6.2V, VSEN=76.0V		100	77	3	0/231
3	UHAST Unbiased Highly Accelerated Stress Test	130°C85%RH		100	77	3	0/231
4	TC Temperature Cycle	-55°C to 150°C		1000CYC.	77	3	0/231
5	HTSL High Temperature Storage Life	150°C		1000	45	1	0/45
6	HTOL High Temperature Operating Life	150°C VIN=6.2V, VSEN=76.0V		1000	77	3	0/231
7	ELFR Early Life Failure Rate	125°C VIN=6.2V, VSEN=76.0V		48	800	3	0/2400
8	SD Solderability	245°C		5 sec.	15	1	0/15 >95% lead coverage
9	HBM Electrostatic Discharge Human Body Model	R=1500Ω C=100pF ±2000V		3 times	5	1	0/5
10	CDM Electrostatic Discharge Charged Device Model	±1000V		3 times	5	1	0/5
11	LU Latch-Up (JEDEC – Class II)	E-test	VIN=9.0V Pulse voltage	1 time	3	1	0/3
		I-test	±200mA	1 time	3	1	0/3